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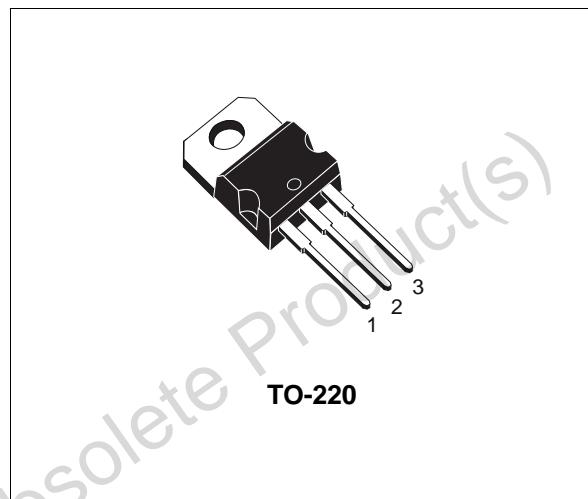


VNP35N07

"OMNIFET": FULLY AUTOPROTECTED POWER MOSFET

TYPE	V _{clamp}	R _{DS(on)}	I _{lim}
VNP35N07	70 V	0.028 Ω	35 A

- LINEAR CURRENT LIMITATION
- THERMAL SHUT DOWN
- SHORT CIRCUIT PROTECTION
- INTEGRATED CLAMP
- LOW CURRENT DRAWN FROM INPUT PIN
- DIAGNOSTIC FEEDBACK THROUGH INPUT PIN
- ESD PROTECTION
- DIRECT ACCESS TO THE GATE OF THE POWER MOSFET (ANALOG DRIVING)
- COMPATIBLE WITH STANDARD POWER MOSFET
- STANDARD TO-220 PACKAGE



DESCRIPTION

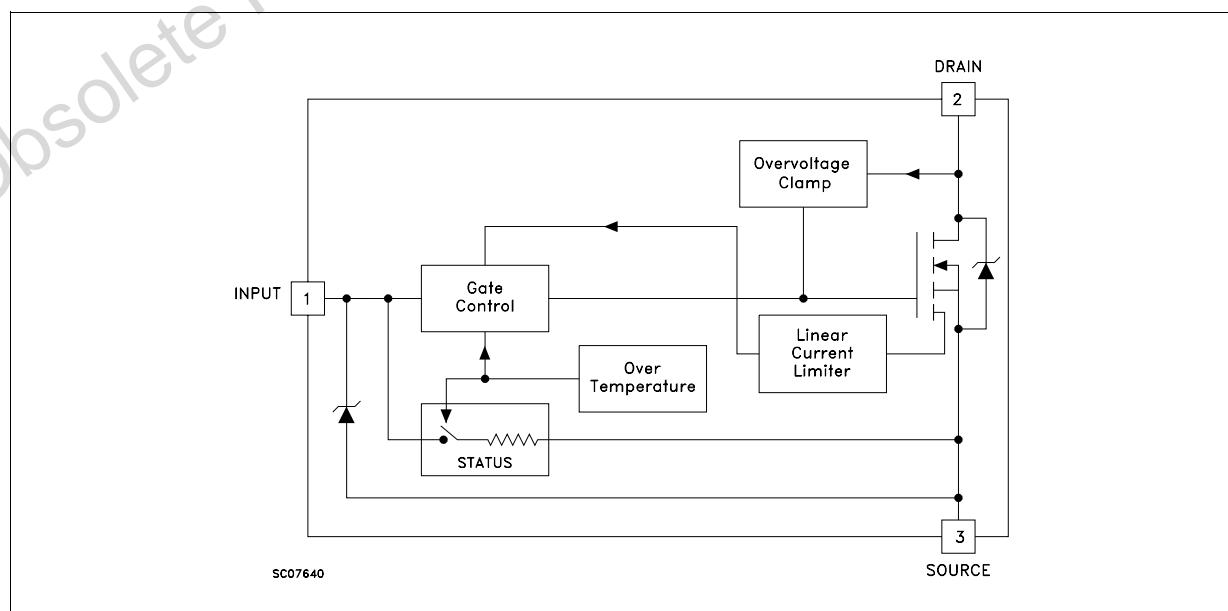
The VNP35N07 is a monolithic device made using STMicroelectronics VIPower Technology, intended for replacement of standard power MOSFETs in DC to 50 KHz applications.

Built-in thermal shut-down, linear current limi-

tation and overvoltage clamp protect the chip in harsh environments.

Fault feedback can be detected by monitoring the voltage at the input pin.

BLOCK DIAGRAM



VNP35N07

ABSOLUTE MAXIMUM RATING

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source Voltage ($V_{in} = 0$)	Internally Clamped	V
V_{in}	Input Voltage	18	V
I_D	Drain Current	Internally Limited	A
I_R	Reverse DC Output Current	-50	A
V_{esd}	Electrostatic Discharge ($C = 100 \text{ pF}, R = 1.5 \text{ k}\Omega$)	2000	V
P_{tot}	Total Dissipation at $T_c = 25^\circ\text{C}$	125	W
T_j	Operating Junction Temperature	Internally Limited	$^\circ\text{C}$
T_c	Case Operating Temperature	Internally Limited	$^\circ\text{C}$
T_{stg}	Storage Temperature	-55 to 150	$^\circ\text{C}$

THERMAL DATA

$R_{thj-case}$	Thermal Resistance Junction-case	Max	1	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal Resistance Junction-ambient	Max	62.5	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^\circ\text{C}$ unless otherwise specified)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{CLAMP}	Drain-source Clamp Voltage	$I_D = 200 \text{ mA} \quad V_{in} = 0$	60	70	80	V
V_{CLTH}	Drain-source Clamp Threshold Voltage	$I_D = 2 \text{ mA} \quad V_{in} = 0$	55			V
V_{INCL}	Input-Source Reverse Clamp Voltage	$I_{in} = -1 \text{ mA}$	-1		-0.3	V
I_{DSS}	Zero Input Voltage Drain Current ($V_{in} = 0$)	$V_{DS} = 13 \text{ V} \quad V_{in} = 0$ $V_{DS} = 25 \text{ V} \quad V_{in} = 0$			50 200	μA
I_{ISS}	Supply Current from Input Pin	$V_{DS} = 0 \text{ V} \quad V_{in} = 10 \text{ V}$		250	500	μA

ON (*)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{IN(th)}$	Input Threshold Voltage	$V_{DS} = V_{in} \quad I_D + I_{in} = 1 \text{ mA}$	0.8		3	V
$R_{DS(on)}$	Static Drain-source On Resistance	$V_{in} = 10 \text{ V} \quad I_D = 18 \text{ A}$ $V_{in} = 5 \text{ V} \quad I_D = 18 \text{ A}$			0.028 0.035	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$g_{fs} \text{ (*)}$	Forward Transconductance	$V_{DS} = 13 \text{ V} \quad I_D = 18 \text{ A}$	20	25		S
C_{oss}	Output Capacitance	$V_{DS} = 13 \text{ V} \quad f = 1 \text{ MHz} \quad V_{in} = 0$		980	1400	pF

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ELECTRICAL CHARACTERISTICS (continued)

SWITCHING (**)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r	Turn-on Delay Time Rise Time	$V_{DD} = 28 \text{ V}$ $I_d = 18 \text{ A}$ $V_{gen} = 10 \text{ V}$ $R_{gen} = 10 \Omega$		100 350	200 600	ns ns
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	(see figure 3)		650 200	1000 350	ns ns
$t_{d(on)}$ t_r	Turn-on Delay Time Rise Time	$V_{DD} = 28 \text{ V}$ $I_d = 18 \text{ A}$ $V_{gen} = 10 \text{ V}$ $R_{gen} = 1000 \Omega$		500 2.7	800 4.2	ns μs
$t_{d(off)}$ t_f	Turn-off Delay Time Fall Time	(see figure 3)		10 4.3	16 6.5	μs μs
$(di/dt)_{on}$	Turn-on Current Slope	$V_{DD} = 28 \text{ V}$ $I_D = 18 \text{ A}$ $V_{in} = 10 \text{ V}$ $R_{gen} = 10 \Omega$		60		$\text{A}/\mu\text{s}$
Q_i	Total Input Charge	$V_{DD} = 12 \text{ V}$ $I_D = 18 \text{ A}$ $V_{in} = 10 \text{ V}$		100		nC

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{SD} (*)$	Forward On Voltage	$I_{SD} = 18 \text{ A}$ $V_{in} = 0$			1.6	V
$t_{rr}(**)$	Reverse Recovery Time	$I_{SD} = 18 \text{ A}$ $di/dt = 100 \text{ A}/\mu\text{s}$		250		ns
$Q_{rr}(**)$	Reverse Recovery Charge	$V_{DD} = 30 \text{ V}$ $T_j = 25^\circ\text{C}$		1		μC
$I_{RRM}(**)$	Reverse Recovery Current	(see test circuit, figure 5)		8		A

PROTECTION

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{lim}	Drain Current Limit	$V_{in} = 10 \text{ V}$ $V_{DS} = 13 \text{ V}$ $V_{in} = 5 \text{ V}$ $V_{DS} = 13 \text{ V}$	25 25	35 35	45 45	A A
$t_{dlim}(**)$	Step Response Current Limit	$V_{in} = 10 \text{ V}$ $V_{in} = 5 \text{ V}$		35 70	60 140	μs μs
$T_{jsh}(**)$	Overtemperature Shutdown		150			$^\circ\text{C}$
$T_{jrs}(**)$	Overtemperature Reset		135			$^\circ\text{C}$
$I_{gf}(**)$	Fault Sink Current	$V_{in} = 10 \text{ V}$ $V_{DS} = 13 \text{ V}$ $V_{in} = 5 \text{ V}$ $V_{DS} = 13 \text{ V}$		50 20		mA mA
$E_{as}(**)$	Single Pulse Avalanche Energy	starting $T_j = 25^\circ\text{C}$ $V_{DD} = 20 \text{ V}$ $V_{in} = 10 \text{ V}$ $R_{gen} = 1 \text{ K}\Omega$ $L = 10 \text{ mH}$	2.5			J

(*) Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %

(**) Parameters guaranteed by design/characterization

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PROTECTION FEATURES

During normal operation, the Input pin is electrically connected to the gate of the internal power MOSFET. The device then behaves like a standard power MOSFET and can be used as a switch from DC to 50 KHz. The only difference from the user's standpoint is that a small DC current (I_{iss}) flows into the Input pin in order to supply the internal circuitry.

The device integrates:

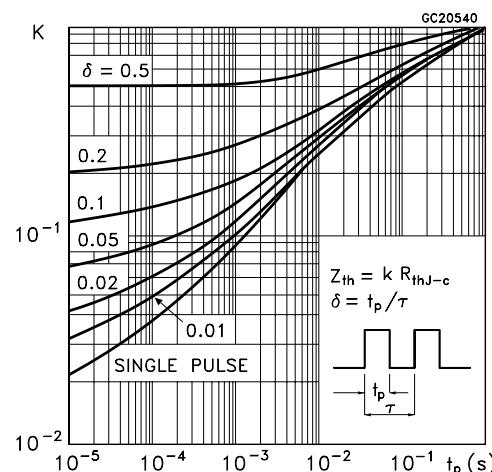
- OVERVOLTAGE CLAMP PROTECTION: internally set at 70V, along with the rugged avalanche characteristics of the Power MOSFET stage give this device unrivalled ruggedness and energy handling capability. This feature is mainly important when driving inductive loads.
- LINEAR CURRENT LIMITER CIRCUIT: limits the drain current I_d to I_{lim} whatever the Input pin voltage. When the current limiter is active, the device operates in the linear region, so power dissipation may exceed the capability of the heatsink. Both case and junction temperatures increase, and if this phase lasts long enough, junction temperature may reach the overtemperature threshold T_{jsh} .

- OVERTEMPERRATURE AND SHORT CIRCUIT PROTECTION: these are based on sensing the chip temperature and are not dependent on the input voltage. The location of the sensing element on the chip in the power stage area ensures fast, accurate detection of the junction temperature. Overtemperature cutout occurs at minimum 150°C. The device is automatically restarted when the chip temperature falls below 135°C.
- STATUS FEEDBACK: In the case of an overtemperature fault condition, a Status Feedback is provided through the Input pin. The internal protection circuit disconnects the input from the gate and connects it instead to ground via an equivalent resistance of 100 Ω. The failure can be detected by monitoring the voltage at the Input pin, which will be close to ground potential.

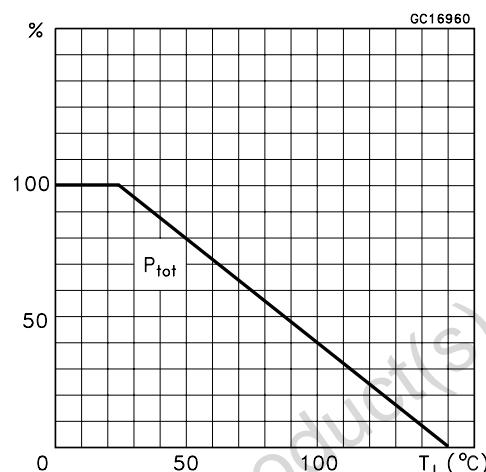
Additional features of this device are ESD protection according to the Human Body model and the ability to be driven from a TTL Logic circuit (with a small increase in $R_{DS(on)}$).

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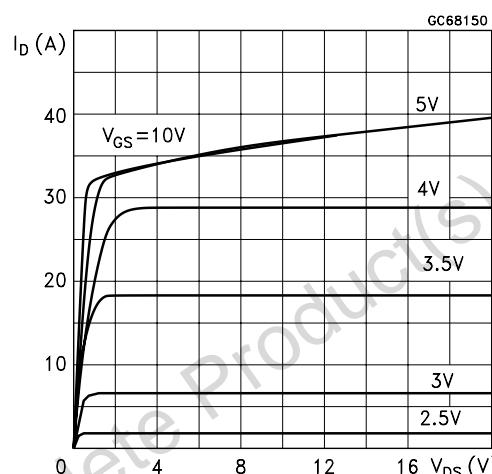
Thermal Impedance



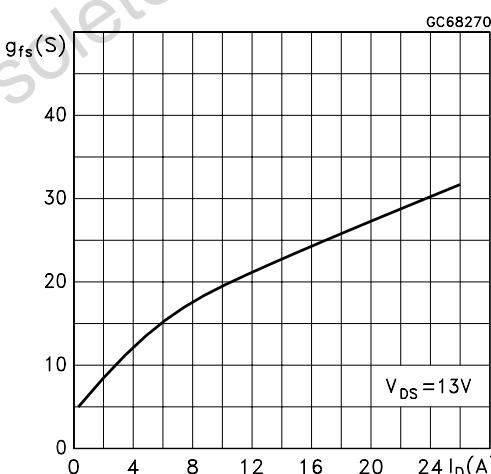
Derating Curve



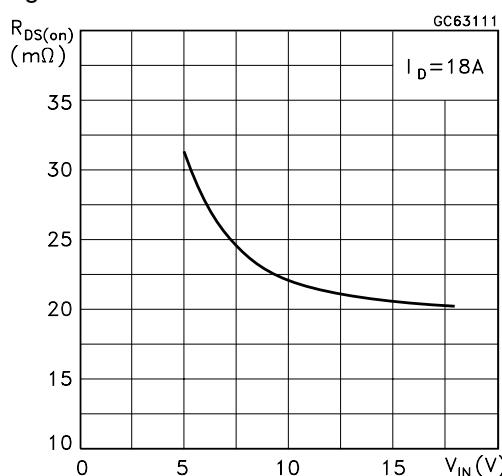
Output Characteristics



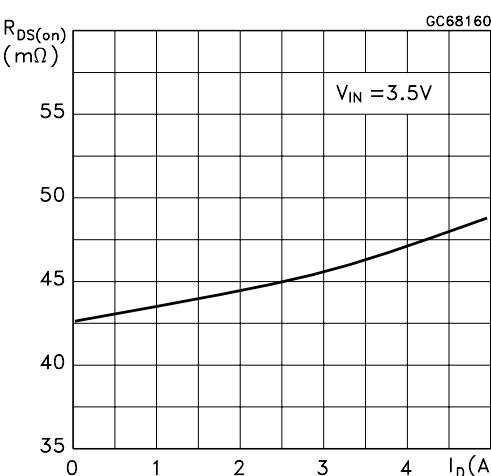
Transconductance



Static Drain-Source On Resistance vs Input Voltage

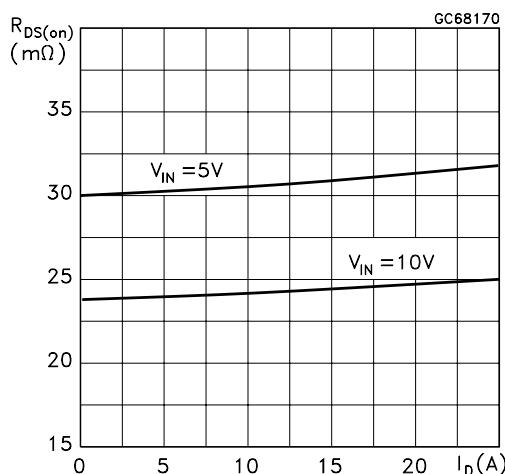


Static Drain-Source On Resistance

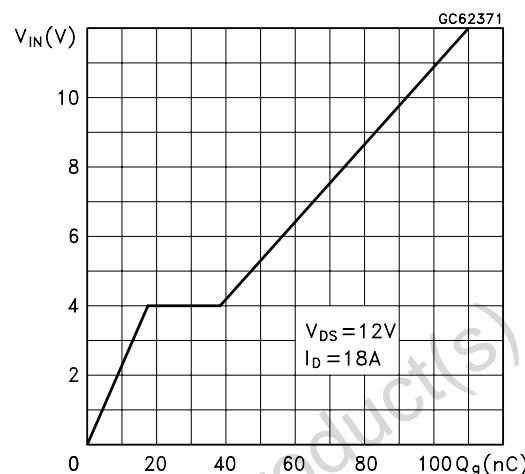


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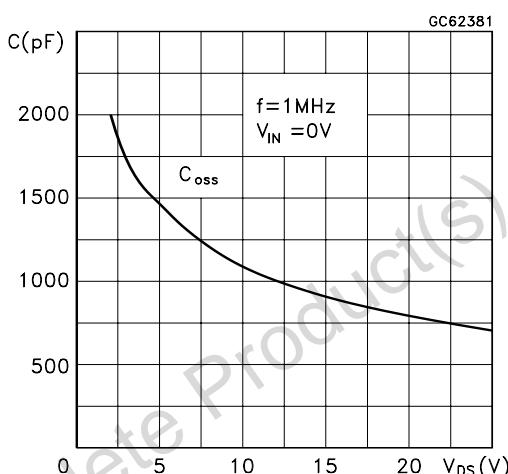
Static Drain-Source On Resistance



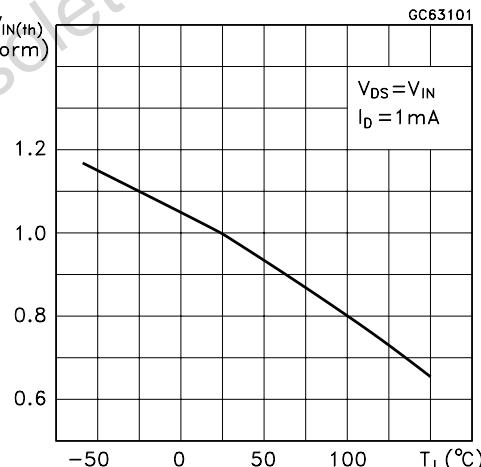
Input Charge vs Input Voltage



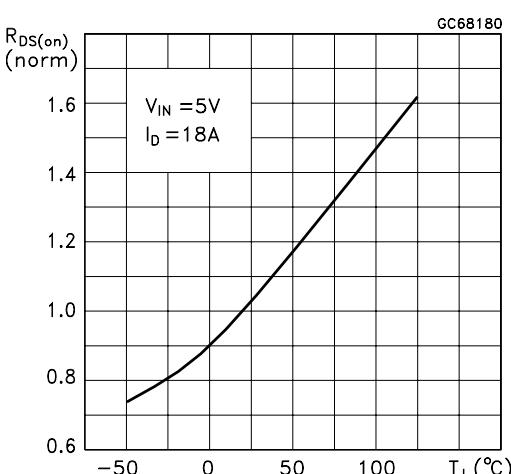
Capacitance Variations



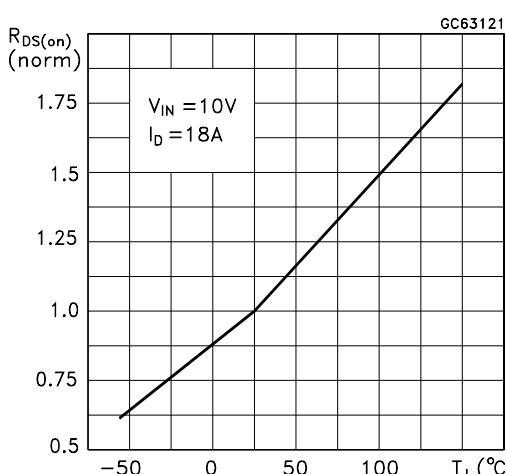
Normalized Input Threshold Voltage vs Temperature



Normalized On Resistance vs Temperature

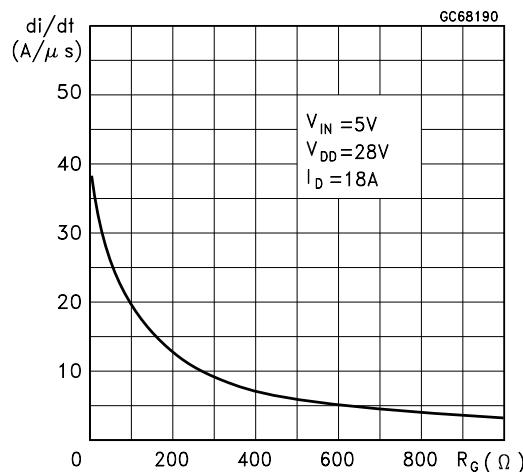


Normalized On Resistance vs Temperature

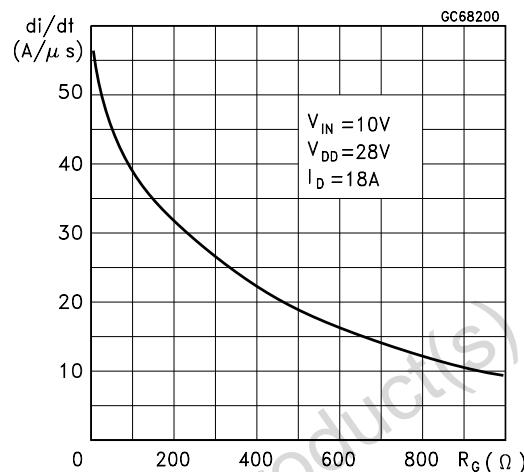


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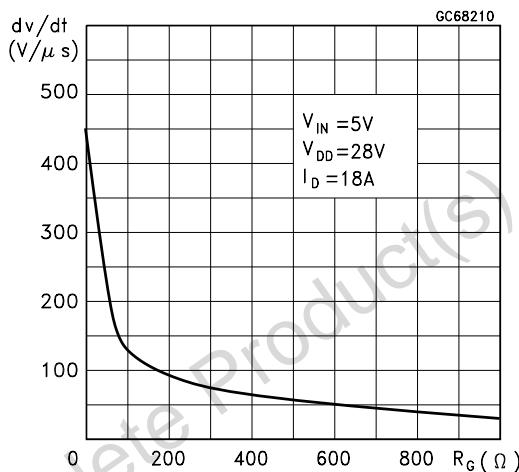
Turn-on Current Slope



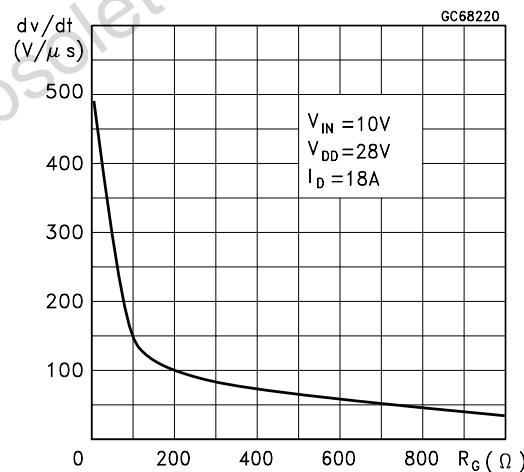
Turn-on Current Slope



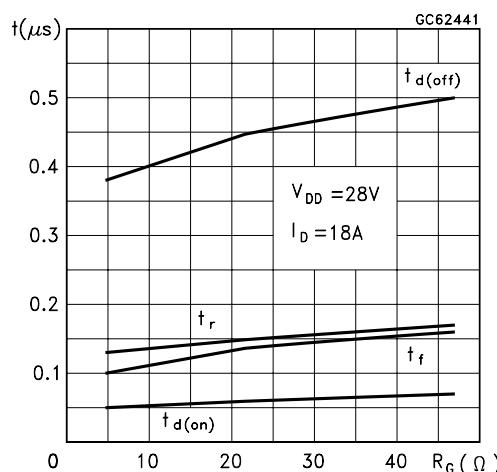
Turn-off Drain-Source Voltage Slope



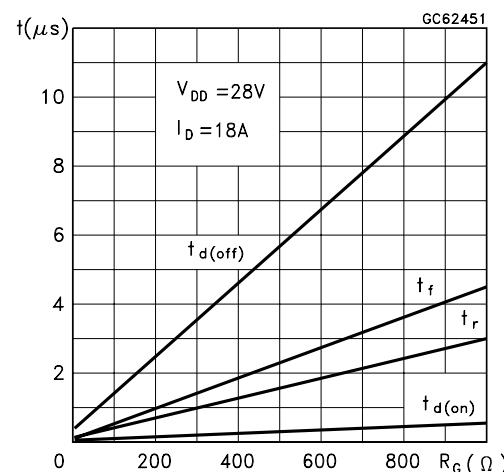
Turn-off Drain-Source Voltage Slope



Switching Time Resistive Load

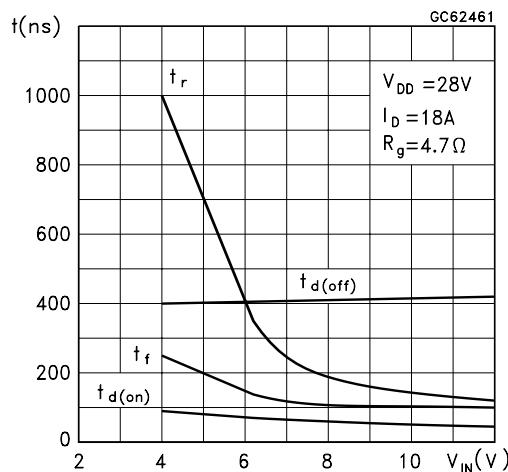


Switching Time Resistive Load

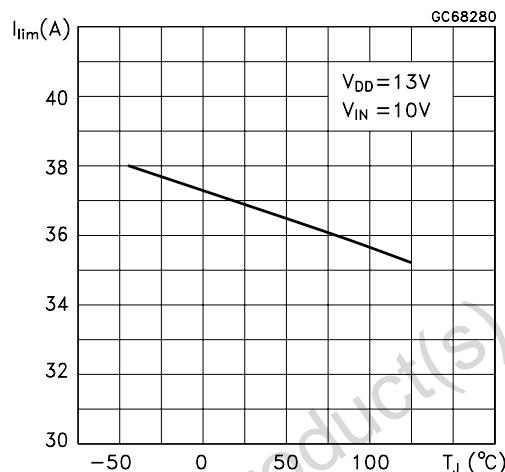


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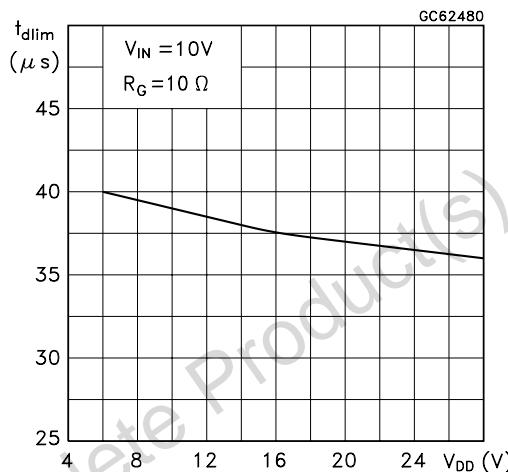
Switching Time Resistive Load



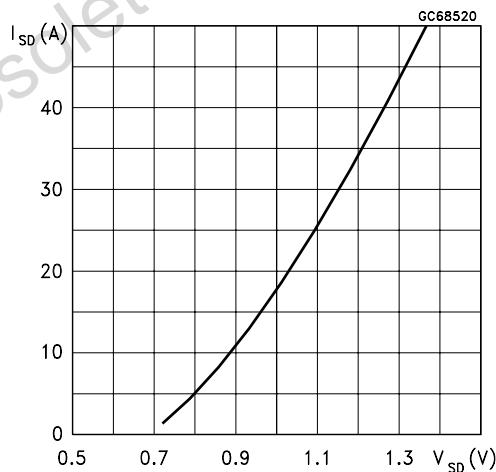
Current Limit vs Junction Temperature



Step Response Current Limit



Source Drain Diode Forward Characteristics



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Fig. 1: Unclamped Inductive Load Test Circuits

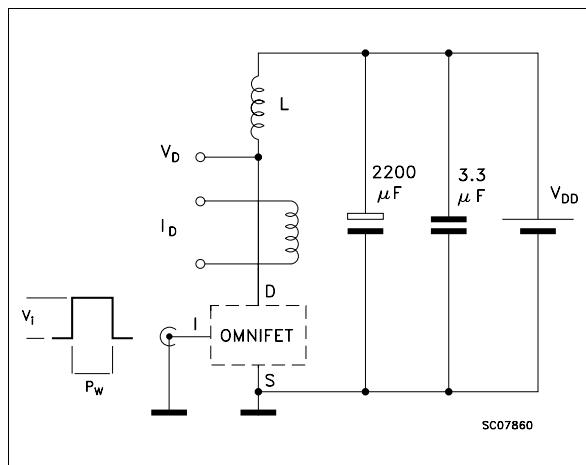


Fig. 2: Unclamped Inductive Waveforms

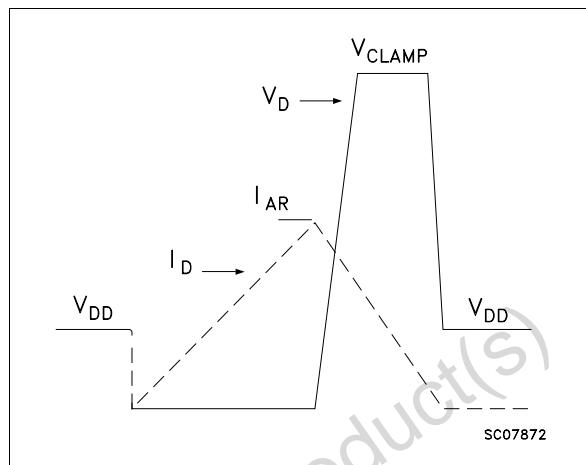


Fig. 3: Switching Times Test Circuits For Resistive Load

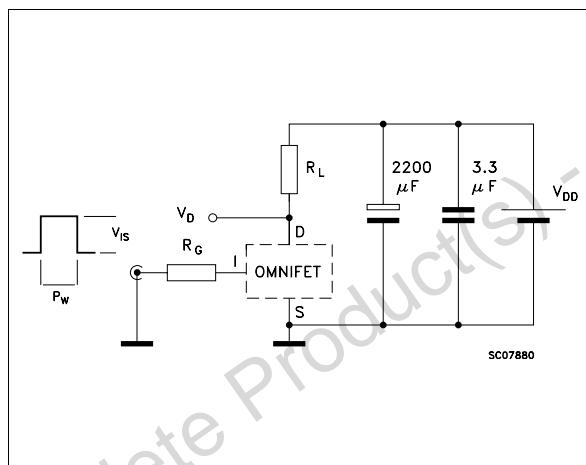


Fig. 4: Input Charge Test Circuit

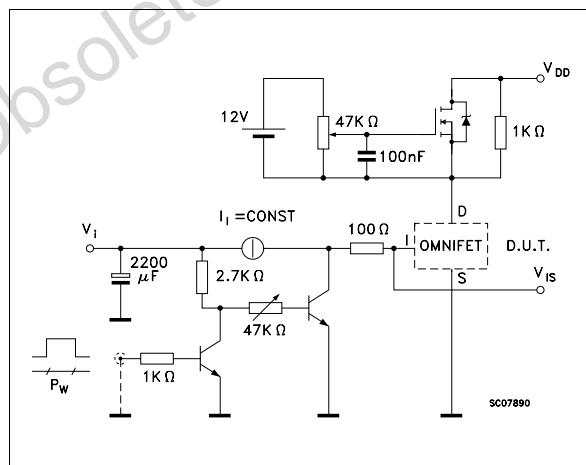


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

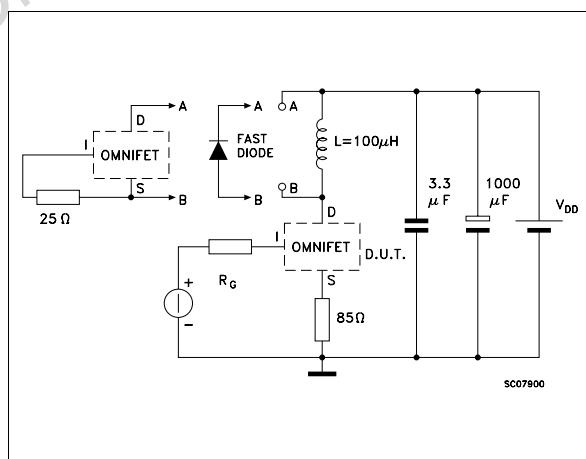
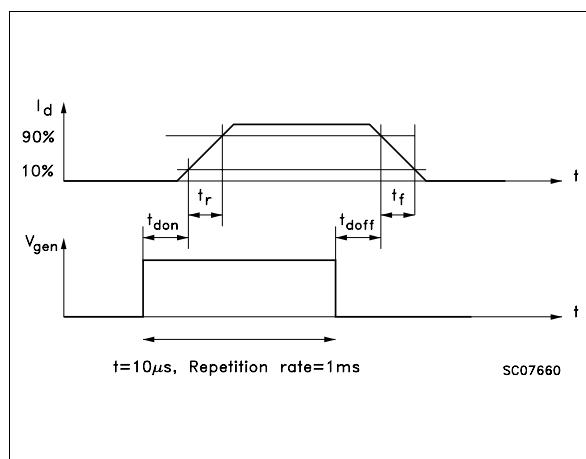


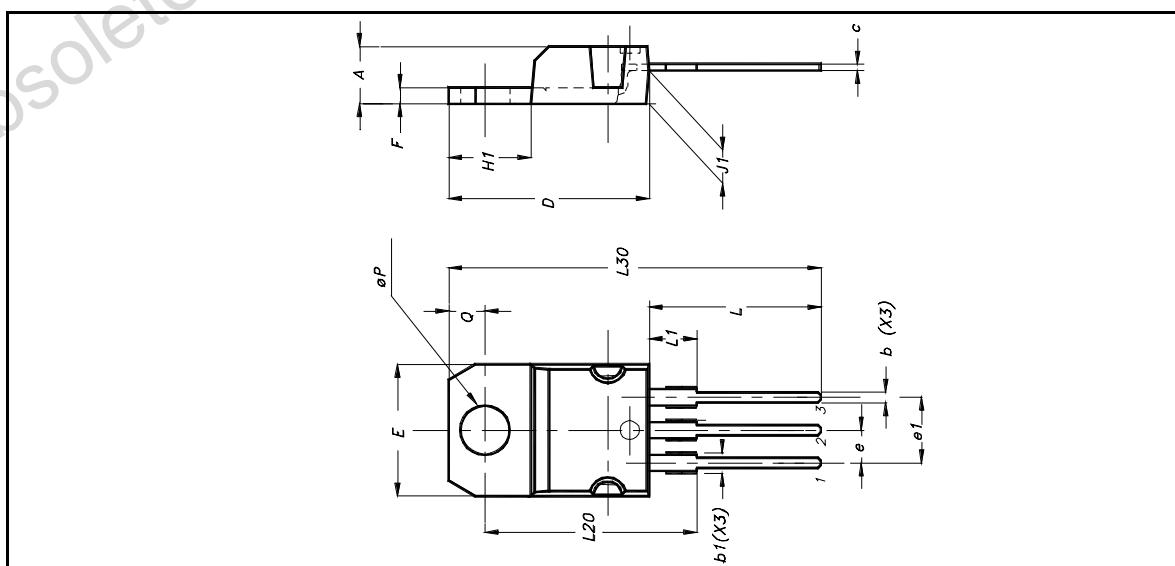
Fig. 6: Waveforms



VNP35N07

TO-220 MECHANICAL DATA

DIM.	mm.		
	MIN.	TYP	MAX.
A	4.40		4.60
b	0.61		0.88
b1	1.15		1.70
c	0.49		0.70
D	15.25		15.75
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95
Package Weight		1.9Gr. (Typ.)	



VNP35N07

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